

## TRADEMARK ASSIGNMENT

Electronic Version v1.1  
 Stylesheet Version v1.1

SUBMISSION TYPE:	NEW ASSIGNMENT		
NATURE OF CONVEYANCE:	SECURITY INTEREST		
CONVEYING PARTY DATA			
Name	Formerly	Execution Date	Entity Type
Qcept Technologies, Inc.		03/01/2012	CORPORATION: DELAWARE
RECEIVING PARTY DATA			
Name:	RBC Bank (USA)		
Street Address:	PO Box 1220		
City:	Rocky Mount		
State/Country:	NORTH CAROLINA		
Postal Code:	27804		
Entity Type:	Bank: NORTH CAROLINA		
PROPERTY NUMBERS Total: 2			
Property Type	Number	Word Mark	
Registration Number:	3669660	QCEPT	
Registration Number:	3118703	CHEMETRIQ	
CORRESPONDENCE DATA			
Fax Number:	(404)853-8806		
Phone:	404-853-8127		
Email:	julie.murphy@sutherland.com		
<i>Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent via US Mail.</i>			
Correspondent Name:	Sutherland Asbill & Brennan LLP		
Address Line 1:	999 Peachtree Street NE		
Address Line 4:	Atlanta, GEORGIA 30309-3996		
ATTORNEY DOCKET NUMBER:	19893-0036		
NAME OF SUBMITTER:	Jessica Rissmiller		
Signature:	/Jessica Rissmiller/		

Date:

03/23/2012

**Total Attachments: 12**

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Customer No. \_\_\_\_\_  
Loan No. \_\_\_\_\_

## RBC Bank (USA)

### Intellectual Property Security Agreement (SD-L&S)

THIS INTELLECTUAL PROPERTY SECURITY AGREEMENT ("Agreement") is entered into as of March 1, 2012 by **QCEPT TECHNOLOGIES INC.**, a Delaware corporation (whether one or more, "Borrower"), with a mailing address of 75 5<sup>TH</sup> Street, Suite 740, Atlanta, Georgia 30308, to **RBC BANK (USA)** ("Bank"), with a mailing address of Post Office Box 1220, Rocky Mount, North Carolina 27804.

#### RECITALS

A. Bank has agreed to extend certain financial accommodations to Borrower ("Credit Facilities") as set forth in that certain Loan and Security Agreement entered into contemporaneously herewith by and between Bank and Borrower (as the same may be amended, modified, extended, renewed, replaced and supplemented from time to time, the "Loan Agreement"). Capitalized terms not defined herein shall have the meaning ascribed thereto in the Loan Agreement.

B. Pursuant to the terms of the Loan Agreement, Borrower has granted to Bank a security interest in presently existing and hereafter acquired Collateral, including the Intellectual Property Collateral, and Borrower is required to supplement the grant of the security interest therein with the grant of the security interest herein contained.

NOW, THEREFORE, for good and valuable consideration paid by Bank, the receipt and sufficiency of which are hereby acknowledged, Borrower hereby represents, warrants, covenants and agrees with Bank as follows:

#### AGREEMENT

1. Grant of Security Interest. To secure the prompt, full and complete payment and performance of the Obligations, both now existing and hereafter arising, and Borrower's other existing and future representations, warranties and covenants under the Loan Documents, Borrower grants and pledges to Bank a security interest in all of Borrower's right, title and interest in, to and under its present, existing and hereafter acquired Intellectual Property Collateral (including, without limitation, those Copyrights, Patents and Trademarks listed on Exhibits A, B, and C attached hereto), together with all proceeds and products thereof (such as, by way of example, but not by way of limitation, license royalties and proceeds of infringement suits), the right to sue for past, present and future infringements, all rights corresponding thereto throughout the world and all re-issues, divisions, continuations, renewals, extensions and continuations-in-part thereof.

2. Rights and Remedies; Exercise. This security interest is granted in conjunction with, and as a supplement to, the security interest granted to Bank under the Loan Agreement. The rights and remedies of Bank with respect to the security interest granted hereby are in addition to those rights and remedies of Bank set forth in the Loan Agreement, the other Loan Documents and those which are now available and may hereafter become available to Bank as a matter of law and equity, including, without limitation, those set forth in the Code as being available to a "secured party" and "creditor". Bank may exercise the aforementioned rights and remedies as and when provided herein, in the Loan Agreement and in the other Loan Documents. Each right, power and remedy of Bank provided for herein, in the Loan Agreement, in any of the other Loan Documents, together with those rights and remedies now and hereafter existing at law and in equity, shall be cumulative and concurrent and the exercise by Bank of any one or more of the aforementioned rights and remedies shall not preclude the simultaneous and later exercise by any person, including Bank, of any or all other rights, powers and remedies.

3. Term. The Loan Agreement and the terms and provisions thereof are incorporated herein in their entirety by this reference. The term of this Agreement and the security interests granted herein shall be coterminous with the term of the security interests granted in the Loan Agreement, and notwithstanding any limitation of,

moratorium on and termination of Bank's obligation to make Credit Extensions under the Loan Agreement, Borrower's obligations under this Agreement shall remain in full force and effect for so long as any Obligations are outstanding. It shall be an Event of Default under the Loan Agreement if there is a breach or violation of any of the terms and provisions of this Agreement.

4. Registered Intellectual Property. Borrower represents and warrants that Exhibits A, B, and C attached hereto set forth any and all intellectual property rights which Borrower has registered or filed a pending application to register with the United States Patent and Trademark Office, the United States Copyright Office, or similar offices in foreign countries governing intellectual property, as applicable.

5. New IP. The rights, duties and obligations outlined in the provisions of this Agreement shall automatically apply to all intellectual property and intellectual property rights, including those set forth in any licenses related to any of the foregoing, which Borrower obtains subsequent to the date of this Agreement ("New IP"). Borrower shall give to Bank written notice of all New IP promptly after the acquisition of same, but in any event not less frequently than as required by the Loan Agreement. Borrower hereby authorizes Bank to (i) modify this Agreement unilaterally by amending the exhibits to this Agreement to include any New IP and (ii) file a duplicate original of this Agreement containing the amended exhibits reflecting the New IP in the manner described in Section 8 of this Agreement.

6. Bank's Use of Intellectual Property; No Liability. Borrower agrees that the Bank's use of the Intellectual Property Collateral as authorized hereunder and in any other Loan Documents in connection with Bank's exercise of its rights and remedies shall be coextensive with Borrower's rights thereunder and Bank will have no liability for royalties and other related charges upon exercise of such rights and remedies.

7. Power of Attorney; Appointment. Borrower irrevocably designates, constitutes and appoints Bank (and all persons designated by Bank in its sole and absolute discretion) as Borrower's true and lawful attorney-in-fact, and authorizes Bank and any of Bank's designees, in Borrower's or Bank's name, to take any action and execute any instrument which Bank may deem necessary or advisable to accomplish the purpose of this Agreement.

8. Filing; Patent Office and Copyright Office. Borrower hereby consents to the filing of a duplicate original of this Agreement with the United States Patent and Trademark Office and United States Copyright Office, and the filing of a duplicate of this Agreement and financing statements in any other jurisdictions and locations deemed advisable or necessary in Bank's sole discretion to protect and perfect and put the public on notice of Bank's security interest and rights in the Intellectual Property Collateral. Borrower further consents to and ratifies the filing of such duplicate originals and financing statements prior to the Closing Date. Borrower shall from time to time execute and deliver to Bank, at the request of Bank, such other documents, instruments and records that Bank may request in form and substance satisfactory to Bank and its counsel, to perfect and continue Bank's security interest in the Intellectual Property Collateral.

9. Governing Law, etc. This Agreement shall be governed by and construed in accordance with the laws of the State of Georgia, excluding therefrom any principle of such laws which might result in the application of the laws of another jurisdiction. In addition, (i) no amendment of and waiver of a right under this Agreement will be binding unless it is in writing and signed by the party to be charged, (ii) to the extent a provision of this Agreement is unenforceable, this Agreement will be construed as if the unenforceable provision were omitted, (iii) a successor to and assignee of Bank's rights and obligations under the Loan Agreement will succeed to Bank's rights under this Agreement and (iv) all notices and other communications required or permitted herein shall be in writing and shall be deemed given when mailed by registered or certified mail, postage prepaid, return receipt requested, addressed to the addresses set forth above.

10. Counterparts. This Agreement may be executed in two or more counterparts, each of which shall be deemed an original but all of which taken together shall constitute the same instrument.

(SIGNATURES ON THE FOLLOWING PAGE)

IN WITNESS WHEREOF, Borrower has caused this Intellectual Property Security Agreement to be executed under seal with authority duly obtained, as of the date first written above.

Signed, sealed and delivered in the presence of:

Witness:

Angelia Austin  
Print Name: Angelia Austin

**QCEPT TECHNOLOGIES, INC.,**  
a Delaware corporation

By: [Signature] (SEAL)  
Name: Bret J. Bergman  
Title: Chief Executive Officer

Patricia B. Baker  
Print Name: PATRICIA B BAKER  
Notary Public

My Commission Expires: 8/11/13

[Notarial Seal]  
**Patricia B. Baker**  
Notary Public  
My Commission Expires  
August 11, 2013  
Fulton County, Georgia

Intellectual Property Security Agreement

**TRADEMARK**  
**REEL: 004743 FRAME: 0286**

EXHIBIT A

**COPYRIGHTS**

Description

Registration  
Number

Registration  
Date

None

1212416  
16312427.3

**TRADEMARK**  
**REEL: 004743 FRAME: 0287**

## EXHIBIT B

### **PATENTS AND PENDING PATENT APPLICATIONS**

#### **ISSUED U.S. PATENTS**

##### **1. SEMICONDUCTOR WAFER INSPECTION SYSTEM**

Patent: 6,957,154 – Non-Provisional Utility Patent  
Assignee: Qcept Technologies Inc.  
Inventors: Steele et al.  
Filed: July 29, 2003  
Issued: October 18, 2005  
Description: Directed to methods and systems for the inspection of semiconductor wafers and other materials such as integrated circuits and any surface benefiting from inspection.

##### **2. INSPECTION SYSTEM AND APPARATUS**

Patent: 7,092,826 – Non-Provisional U.S. Utility Patent  
Assignee: Qcept Technologies Inc.  
Inventors: Steele et al.  
Filed: June 17, 2005  
Issued: August 15, 2006  
Description: This continuation patent contains 28 claims that are similar to the claims in Qcept's issued patent no. 6,957,154 as it is a "placeholder" for the priority date of the original patent.  
Comments: Continuation of U.S. Utility Patent 6,957,154 issued October 18, 2005.

##### **3. INSPECTION SYSTEM AND APPARATUS**

Patent: 7,103,482 – Non-Provisional U.S. Utility Patent  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne et al.  
Filed: August 5, 2004  
Issued: September 5, 2006  
Description: Describes claims that deal with a variety of improvements that have been implemented for scanning systems. Also, claims that deal with the ability to apply bias voltages to the probe and with inspecting the surface of a sample without specifying the type of sample or the type of inspection.  
Comments: Continuation-In-Part of Imaging and Analysis of Chemical Contamination on Semiconductor Wafers using a Non-Vibrating CPD Sensor, U.S. Pat 7,308,367.

##### **4. INSPECTION SYSTEM AND APPARATUS**

Patent: 7,107,158 – Non-Provisional U.S. Utility Patent  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne  
Filed: March 11, 2005  
Issued: September 12, 2006  
Description: Claims related to combined vibrating and non-vibrating contact potential difference imaging and measurement system  
Comments: Continuation-In-Part of Inspection System and Apparatus, U.S. Pat. 7,103,482. Applications pending for PCT, EPO, Taiwan, Japan, S. Korea and China.

##### **5. MEASUREMENTS OF MOTIONS OF ROTATING SHAFTS USING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent: 7,152,476 – Non-Provisional U.S. Utility Patent  
Assignee: Qcept Technologies Inc.  
Inventors: Jeffrey A. Hawthorne; M. Brandon Steele  
Filed: July 23, 2004

Issued: December 26, 2006  
Description: Relates to measurement methods and systems using non-vibrating contact potential difference sensors  
Comments: No foreign applications will be filed on this patent.

#### **6. WAFER INSPECTION SYSTEM**

Patent: 7,308,367 – Non-Provisional U.S. Utility Patent  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne et al.  
Filed: February 3, 2004  
Issued: December 11, 2007  
Description: This continuation patent expands upon the issued patent below in that it includes a method for calculating the scan height and method for determining the height of the sensor.  
Comments: Continuation of U.S. Utility Patent 6,957,154 issued October 18, 2005.

#### **7. INSPECTION SYSTEM AND APPARATUS**

Patent: 7,337,076 – Non-Provisional U.S. Utility Patent  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne et al.  
Filed: September 12, 2006  
Issued: February 26, 2008  
Description: This continuation patent expands upon the issued patent and makes claim to a method and system for the characterization of microscopic and macroscopic defects through imaging and visualization of the CPD topology on the wafer surface through the use of a non-vibrating CPD sensor in combination with a vibrating CPD sensor.  
Comments: Continuation of U.S. Utility Patent 7,107,158 issued September 12, 2006.

#### **8. SEMICONDUCTOR WAFER INSPECTION SYSTEM**

Patent: 7,379,826 B2 – Non-Provisional U.S. Utility Patent  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne et al.  
Filed: August 15, 2006  
Issued: May 27, 2008  
Description: This continuation patent expands upon the issued patent below in that it provides improved methods of processing CPD data to identify defects on the surface of a wafer.  
Comments: Continuation of U.S. Utility Patent 7,092,826 issued August 15, 2006.  
Assignment: None Recorded with U.S. Patent and Trademark Office.  
Liens: None recorded with U.S. Patent and Trademark Office.

#### **9. INSPECTION SYSTEM AND APPARATUS UTILIZING VIBRATING & NON-VIBRATING CPD SENSOR**

Patent: 7,634,365 B2 – Non-Provisional U.S. Utility Patent  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne, et al.  
Filed: February 25, 2008  
Issued: December 15, 2009  
Description: This continuation patent expands upon the issued patent and is directed to methods and systems for the inspection of semiconductor wafers and other materials such as integrated circuits and any surface benefitting from inspection.  
Comments: Continuation of U.S. Utility Patent 7,337,076 issued February 26, 2008.

#### **10. SEMICONDUCTOR INSPECTION SYSTEM AND APPARATUS UTILIZING A NON-VIBRATING CPD SENSOR AND CONTROLLED ILLUMINATION**



Patent: 7,659,734 – Non-Provisional U.S. Utility Patent  
Assignee Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne  
Filed: March 7, 2007  
Issued: February 9, 2010  
Description: Method and system for identifying a defect or contamination, using controlled illumination, on the surface of a semiconductor or in a semiconductor.  
Comments: N/A

**11. CALIBRATION OF NON-VIBRATING CPD MEASUREMENTS TO DETECT SURFACE VARIATIONS THAT ARE PERPENDICULAR TO THE DIRECTION OF THE SENSOR MOTION**

Patent: 7,752,000 B2– Non-Provisional U.S. Utility Patent  
Assignee Qcept Technologies Inc.  
Inventors: Mark Schulze, William Usry  
Filed: May 2, 2008  
Issued: July 6, 2010  
Description: Method using a non-vibrating CPD probe and a vibrating CPD probe to determine the contact potential difference of a wafer surface.  
Comments: N/A

**12. DEFECT CLASSIFICATION UTILIZING DATA FROM A NON-VIBRATING CPD SENSOR**

Patent: 7,900,526 – Non-Provisional U.S. Utility Patent  
Assignee Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey Alan Hawthorne, Yeyuan Yang, Mark Schulze  
Filed: March 8, 2011  
Description: A method and system for identifying and classifying non-uniformities on the surface of a semiconductor or in a semiconductor.  
Comments: N/A

**PENDING U.S. PATENT APPLICATIONS**

**1. PATTERNED WAFER INSPECTION SYSTEM USING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent Application: 12/694116 – Non-Provisional U.S. Utility Patent  
Assignee Qcept Technologies Inc.  
Inventors: Jun Liu, Jeffrey Alan Hawthorne, Mark Schulze  
Filed: January 26, 2010  
Description: A method and system for identifying and classifying non-uniformities that are not part of a repeating pattern on the surface of a semiconductor or in a semiconductor.  
Comments: N/A

**ISSUED FOREIGN PATENTS:**

**1. SEMICONDUCTOR INSPECTION SYSTEM UTILIZING NON-VIBRATING CPD SENSOR AND CONTROLLED ILLUMINATION**

Patent: KR 0929768  
Assignee Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne  
Issued: February 28, 2008  
Comments: Based on U.S. Patent No. 7,659,734

**2. WAFER INSPECTION SYSTEM**

Patent: FR 1711801

Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne  
Issued: June 17, 2009  
Comments: Based on U.S. Patent No. 7,308,367

### **3. INSPECTION SYSTEM AND APPARATUS**

Patent: European Grant No. 1 869 436 B1  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne  
Issued: October 7, 2009  
Comments: Based on U.S. Patent No. 7,107,158

### **4. WAFER INSPECTION SYSTEM**

Patent: DE 602004021637.2  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne  
Issued: October 7, 2009  
Comments: Based on U.S. Patent No. 7,308,367

### **5. INSPECTION SYSTEM AND APPARATUS**

Patent: FR 1869436  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne  
Issued: October 7, 2009  
Comments: Based on U.S. Patent No. 7,107,158

### **6. INSPECTION SYSTEM AND APPARATUS**

Patent: DE 602006009637.2-08  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey A. Hawthorne  
Issued: October 7, 2009  
Comments: Based on U.S. Patent No. 7,107,158

### **7. SYSTEM FOR INLINE PROCESSING OF A MATERIAL**

Patent: R.O.C. (TAIWAN) I317809  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey Alan Hawthorne  
Issued: December 1, 2009  
Comments: Based on U.S. Patent No. 7,107,158

### **8. INSPECTION SYSTEM AND APPARATUS**

Patent: JP 4 459 289  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey Alan Hawthorne  
Issued: February 19, 2010  
Comments: Based on U.S. Patent No. 7,107,158

### **9. SYSTEM FOR INLINE PROCESSING OF A MATERIAL**

Patent: KR 0950641  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey Alan Hawthorne  
Issued: March 24, 2010  
Comments: Based on U.S. Patent No. 7,107,158

#### **10. INSPECTION SYSTEM AND APPARATUS**

Patent: R.O.C. (TAIWAN) I350914  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey Alan Hawthorne  
Issued: March 24, 2010  
Comments: Based on U.S. Patent No. 7,107,158

#### **11. INSPECTION SYSTEM AND APPARATUS**

Patent: CHINA - ZL200680001263.8  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey Alan Hawthorne  
Issued: October 21, 2011  
Comments: Based on U.S. Patent No. 7,107,158

#### **12. METHOD AND SYSTEM FOR DETECTING NON-UNIFORMITIES OF A SEMICONDUCTOR WAFER**

Patent: R.O.C. (TAIWAN) I346776  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey Alan Hawthorne, Yeyuan Yang, Mark Schulze  
Issued: April 24, 2011  
Comments: Based on U.S. Patent No. 7,659,734

#### **13. SEMICONDUCTOR INSPECTION SYSTEM AND APPARATUS UTILIZING A NON-VIBRATING CPD SENSOR AND CONTROLLED ILLUMINATION**

Patent: JAPAN 4 783 801  
Assignee: Qcept Technologies Inc.  
Inventors: M. Brandon Steele, Jeffrey Alan Hawthorne, Yeyuan Yang, Mark Schulze  
Issued: July 15, 2011  
Comments: Based on U.S. Patent No. 7,659,734

#### **FOREIGN PATENT APPLICATIONS**

##### **1. CALIBRATION OF NON-VIBRATING CONTACT POTENTIAL DIFFERENCE MEASUREMENTS TO DETECT SURFACE VARIATIONS THAT ARE PERPENDICULAR TO THE DIRECTION OF SENSOR MOTION**

Patent: TAIWAN – 9 811 437 5  
Assignee: Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Usry William R.  
Filed: April 30, 2009  
Comments: Based on U.S. Application No. 12/151,054

##### **2. PATTERNED WAFER INSPECTION SYSTEM USING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent: PCT/US2010/022139  
Assignee: Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Liu Jun; Hawthorne Jeffrey Alan.  
Filed: January 26, 2010  
Comments: Based on Provisional Appl. No. 61/149605

##### **3. PATTERNED WAFER INSPECTION SYSTEM USING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent: TAIWAN – 9 910 240 8

Assignee: Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Liu Jun; Hawthorne Jeffrey Alan.  
Filed: January 28, 2010  
Comments: Based U.S. Application No. 61/149605

**4. DEFECT CLASSIFICATION UTILIZING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent: EPO - 0 885 7056.9  
Assignee: Qcept Technologies Inc.  
Inventors: Hawthorne Jeffrey Alan; Steele M. Brandon; Yang Yeyuan; Schulze Mark A.  
Filed: November 25, 2008  
Comments: Based on U.S. Application No. 7900526

**5. CALIBRATION OF NON-VIBRATING CONTACT POTENTIAL DIFFERENCE MEASUREMENTS TO DETECT SURFACE VARIATIONS THAT ARE PERPENDICULAR TO THE DIRECTION OF SENSOR MOTION**

Patent: CHINA – 2009/80115697.4  
Assignee: Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Usry William R.  
Filed: April 28, 2009  
Comments: Based on U.S. Application No. 7752000

**6. CALIBRATION OF NON-VIBRATING CONTACT POTENTIAL DIFFERENCE MEASUREMENTS TO DETECT SURFACE VARIATIONS THAT ARE PERPENDICULAR TO THE DIRECTION OF SENSOR MOTION**

Patent: EPO - 09739580.0  
Assignee: Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Usry William R..  
Filed: April 28, 2009  
Comments: Based on U.S. Application No. 7752000

**7. CALIBRATION OF NON-VIBRATING CONTACT POTENTIAL DIFFERENCE MEASUREMENTS TO DETECT SURFACE VARIATIONS THAT ARE PERPENDICULAR TO THE DIRECTION OF SENSOR MOTION**

Patent: SOUTH KOREA – 10-2010-7023566  
Assignee: Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Usry William R.  
Filed: April 28, 2009  
Comments: Based on U.S. Application No. 7752000

**8. CALIBRATION OF NON-VIBRATING CONTACT POTENTIAL DIFFERENCE MEASUREMENTS TO DETECT SURFACE VARIATIONS THAT ARE PERPENDICULAR TO THE DIRECTION OF SENSOR MOTION**

Patent: JAPAN – 2011-507577  
Assignee: Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Usry William R.  
Filed: April 28, 2009  
Comments: Based on U.S. Application No. 7752000

**9. PATTERNED WAFER INSPECTION SYSTEM USING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent: EPO - 10738973.6  
Assignee: Qcept Technologies Inc.

Inventors: Schulze Mark A.; Liu Jun; Hawthorne Jeffrey Alan  
Filed: January 26, 2010  
Comments: Based on Provisional Application No. 61/149605

**10. PATTERNED WAFER INSPECTION SYSTEM USING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent JAPAN - 2011-548235  
Assignee Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Liu Jun; Hawthorne Jeffrey Alan  
Filed: January 26, 2010  
Comments: Based on Provisional Application No. 61/149605

**11. PATTERNED WAFER INSPECTION SYSTEM USING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent SOUTH KOREA - 10-2011-7017506  
Assignee Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Liu Jun; Hawthorne Jeffrey Alan  
Filed: January 26, 2010  
Comments: Based on Provisional Application No. 61/149605

**12. PATTERNED WAFER INSPECTION SYSTEM USING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent CHINA - 201080005600.7  
Assignee Qcept Technologies Inc.  
Inventors: Schulze Mark A.; Liu Jun; Hawthorne Jeffrey Alan  
Filed: January 26, 2010  
Comments: Based on Provisional Application No. 61/149605

**13. DEFECT CLASSIFICATION UTILIZING A NON-VIBRATING CONTACT POTENTIAL DIFFERENCE SENSOR**

Patent TAIWAN – 9 714 590 8  
Assignee Qcept Technologies Inc.  
Inventors: Hawthorne Jeffrey Alan; Steele M. Brandon; Yang Yeyuan; Schulze Mark A.  
Filed: November 27, 2008  
Comments: Based on U.S. Utility Application No. 11/948518

EXHIBIT C

**TRADEMARKS**

**QCEPT**

On August 18, 2009, the Corporation was granted Registration S/N 3669660 for the mark QCEPT®.

**CHEMETRIQ**

On July 25, 2006, the Corporation was granted Registration S/N 76588252 for the mark CHEMETRIQ®.